

Figure 1

identifying parameters and making list

measuring first parameter on FAB A device (1-n)

calculating  $P_{1A}$  &  $P_{99A}$ .

measuring first parameter on FAB B devices (1-m)  
and calculating  $P_{1B}$  &  $P_{99B}$ .

combining FAB A & FAB B data, determining  
 $P_1 = \max[P_{1A}, P_{1B}]$  &  $P_{99} = \min[P_{99A}, P_{99B}]$ .

determining  $X_{(k-1)} < P_1 \leq X_{(k)}$ ;  $(p) \leq P_{99} < X_{(p+1)}$  and calculating  $S_{AB} = ((p-k+1) / (m+n)) / 98\%$ .

If  $98\% \leq S_{AB}$ , FAB A and FAB B are equal wrt first parameter.

repeating steps 102 – 108 on other parameters on list

If all  $S_{AB}$ 's are greater or equal to 98%, FAB A and FAB B are equal.

Figure 2

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identifying parameters and making list

measuring first parameter on FAB A baseline device (1-n)

recording data 1 to n.

calculating  $P_1$  &  $P_{99}$  from data 1 to n.

measuring first parameter on FAB B devices (1-m) and recording data

using FAB B data, determining  $X_{(k-1)} < P_1 \leq X_{(k)}$ ;  $X_{(p)} \leq P_{99} < X_{(p+1)}$  and calculating  $S_{AB} = ((p-k+1) / m) / 98\%$ .

calculating  $S_B = ((p-k+1) / m) / 98\%$ .

If  $98\% \leq S_B$ , FAB B devices conform to baseline wrt first parameter.

repeating steps 102 – 108 on other parameters on list

If all  $S_B$ 's are greater or equal to 98%, FAB B devices conform to baseline.

Figure 3

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identifying parameters and making list

measuring first parameter on FAB A device (1-n)

recording FAB A data (1-n)

arranging FAB A data in arrayA.

Inserting pre-determined limits C and D  
into array and determining  $X_{(k-1)} < C \leq X_{(k)}$ ;  $(p) \leq D < X_{(p+1)}$

calculating  $CD_{SA} = ((p-k+1) / (n)) / 98\%$ .

If  $98\% \leq CD_{SA}$ , FAB A devices conform to pre-determined limit wrt first parameter.

repeating steps 302 – 308 on other parameters on list

If all  $CD_{SA}$ 's are greater or equal to 98%, FAB A devices conform to pre-determined limit in total